

SE2060

N-Channel Enhancement-Mode MOSFET

Revision: A

General Description

Thigh Density Cell Design For Ultra Low On-Resistance Fully Characterized Avalanche Voltage and Current Improved Shoot-Through FOM

- Simple Drive Requirement
- Small Package Outline
- Surface Mount Device

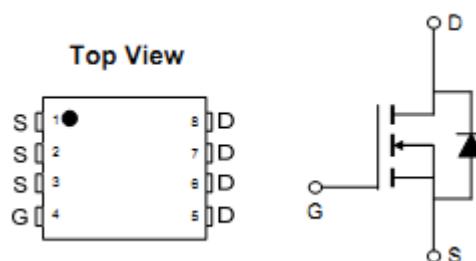
Features

For a single MOSFET

- $V_{DS} = 20V$
- $R_{DS(ON)} = 5.5m\Omega @ V_{GS}=4.5$
- $R_{DS(ON)} = 8m\Omega @ V_{GS}=2.5$

Pin configurations

See Diagram below



Absolute Maximum Ratings

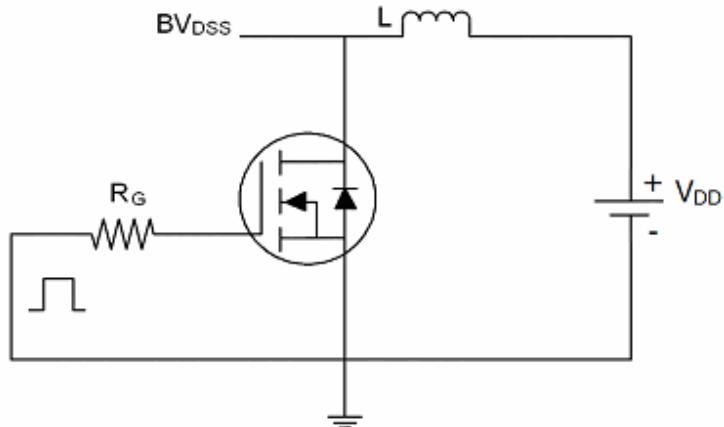
Parameter	Symbol	Rating	Units
Drain-Source Voltage	V_{DS}	20	V
Gate-Source Voltage	V_{GS}	± 12	V
Drain Current	Continuous	I_D	A
	Pulsed		
Total Power Dissipation @TA=25°C	P_D	3	W
Operating Junction Temperature Range	T_J	-55 to 150	°C

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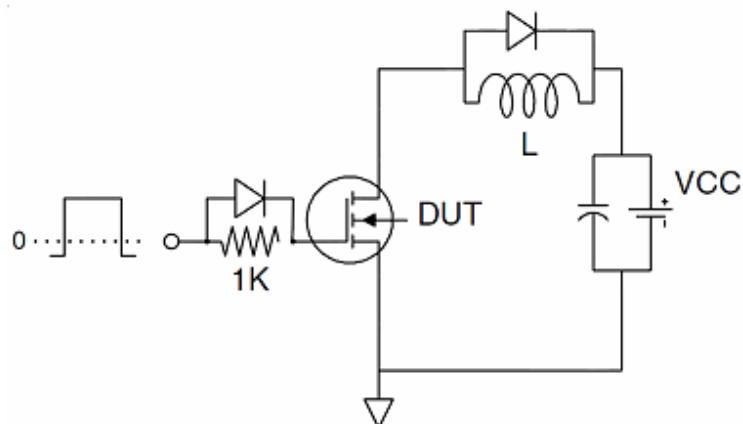
Electrical Characteristics (TJ=25°C unless otherwise noted)						
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS (Note 2)						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0 V	20			V
I _{DSS}	Drain to Source Leakage Current	V _{DS} = 20V, V _{GS} =0V			1	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =12V			100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D =250μA	0.5	0.8	1.4	V
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =4.5V, I _D =20A	-	5.5	8	mΩ
		V _{GS} =2.5V, I _D =15A		8	11	
DYNAMIC PARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0V, f=1MHz		2000		pF
C _{oss}	Output Capacitance			500		pF
C _{rss}	Reverse Transfer Capacitance			200		pF
SWITCHING PARAMETERS						
Q _g	Total Gate Charge ²	V _{GS} =10V, I _D =20A		27		nC
Q _{gs}	Gate Source Charge			6.5		nC
Q _{gd}	Gate Drain Charge			6.4		nC
t _{d(on)}	Turn-On Delay Time	V _{GS} =4.5V, V _{DS} =10V, R _{GEN} =3Ω I _D =2A		6.4		ns
t _{d(off)}	Turn-Off Delay Time			29.6		ns
t _{d(r)}	Turn-On Rise Time			17.2		ns
t _{d(f)}	Turn-Off Fall Time			16.8		ns
Thermal Resistance						
Symbol	Parameter		Typ	Max	Units	
R _{θJC}	Junction to Case		-	2.1		°C/W

Test Circuits and Waveform

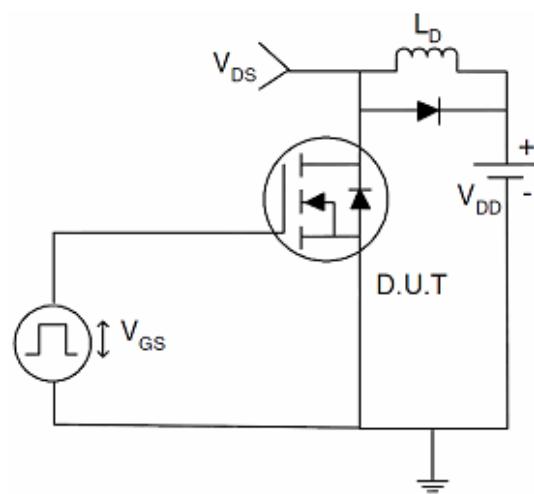
1) E_{AS} Test Circuits



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



Typical Characteristics

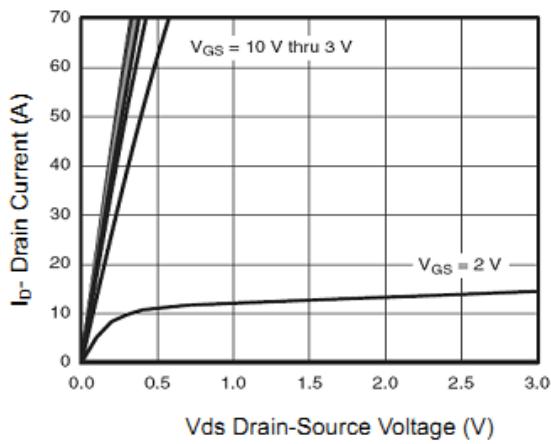


Figure 1 Output Characteristics

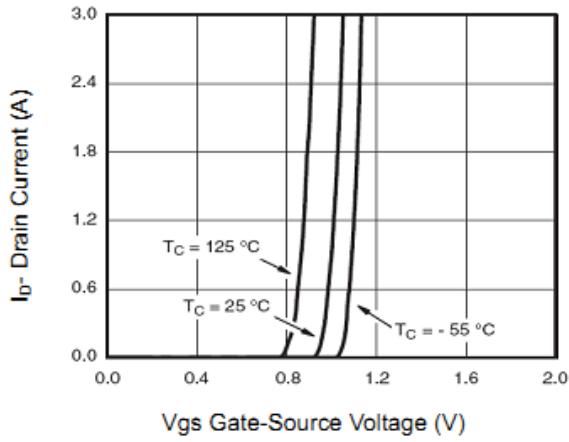


Figure 2 Transfer Characteristics

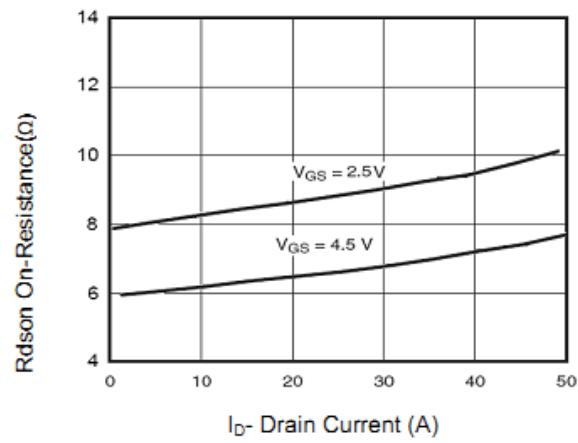


Figure 3 Rdson- Drain Current

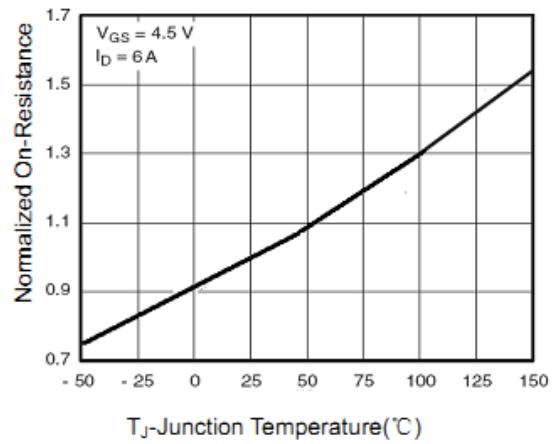


Figure 4 Rdson-Junction Temperature

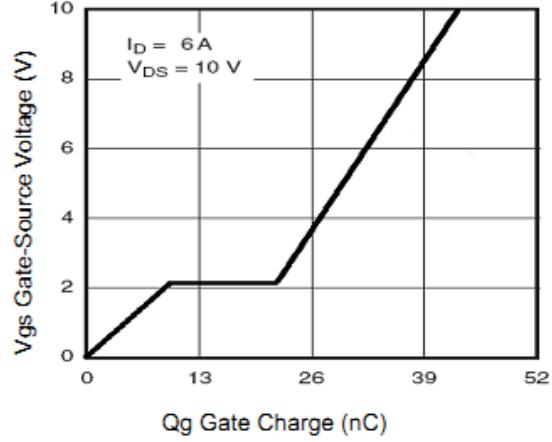


Figure 5 Gate Charge

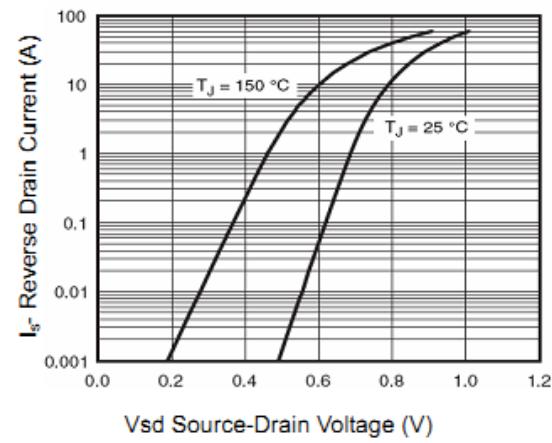


Figure 6 Source- Drain Diode Forward

Typical Characteristics

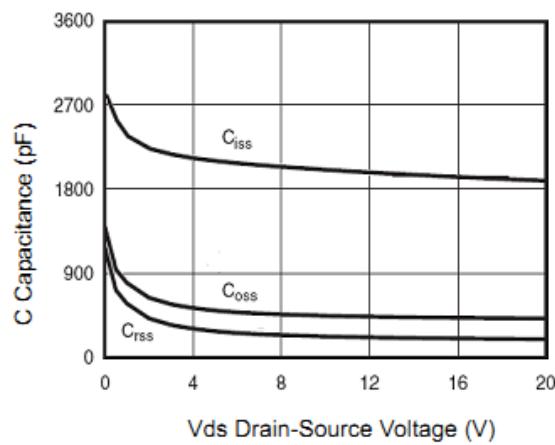


Figure 7 Capacitance vs Vds

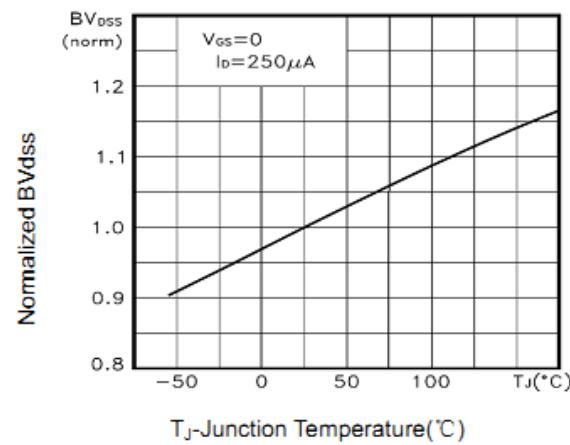
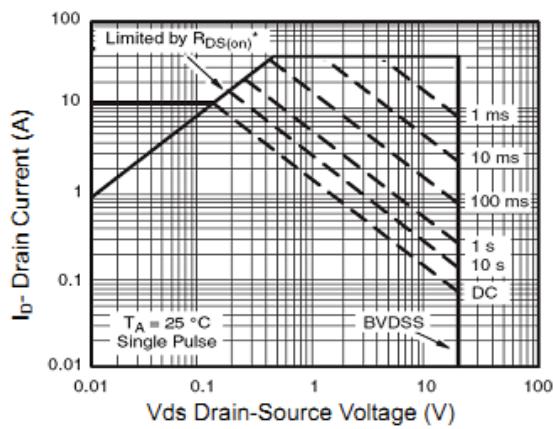
Figure 9 BV_{DSS} vs Junction Temperature

Figure 8 Safe Operation Area

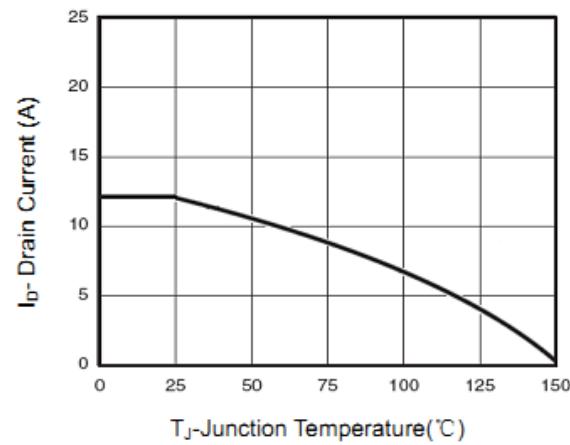


Figure 10 Current vs Junction Temperature

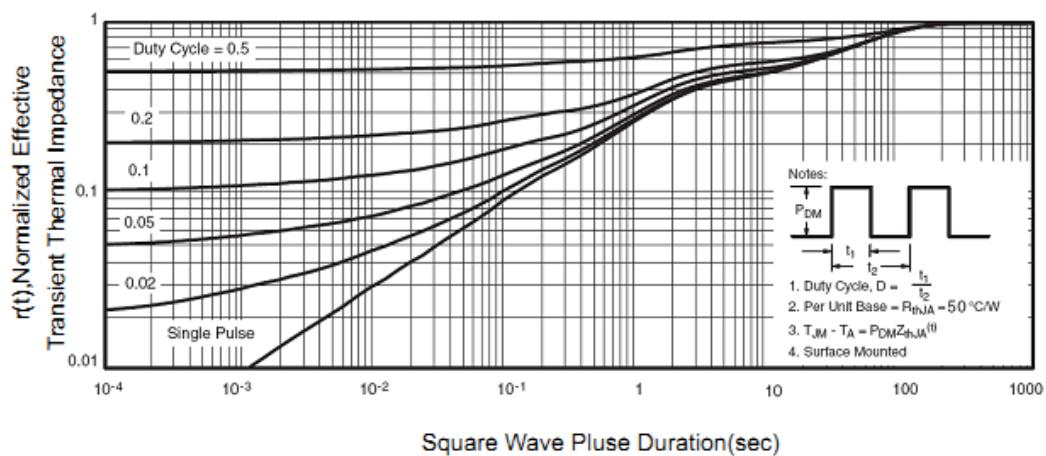


Figure 11 Normalized Maximum Transient Thermal Impedance

Package Outline Dimension

DFN3X3 EP

